

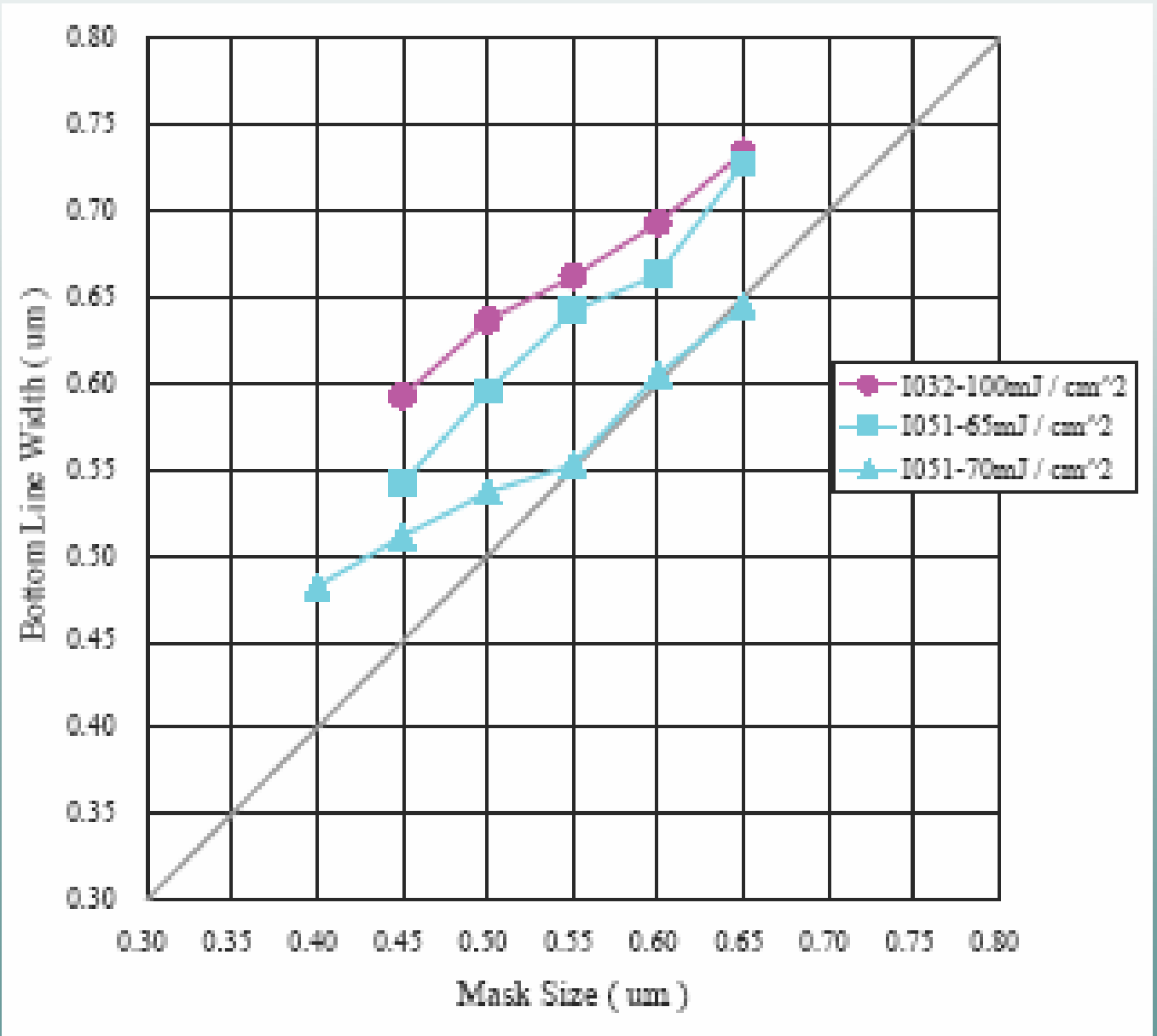
Linearity Data of
SEPR-I051 on Cu

Film Thickness: 3.5 μ m Prebake: 120°C x 240 sec

Exp.: NSR-2005Ex8A , (NA = 0.50, σ = 0.70)

Mask: (S/L = 1/1) Focus: \pm 0.0 μ m PED: 30 min., PEB: 100°C x 120 sec

Dev.: 50 sec x 3 times (SSFD-238N [TMAH = 2.38%])



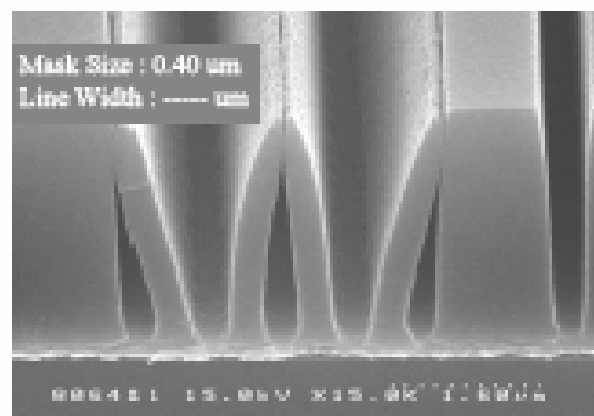
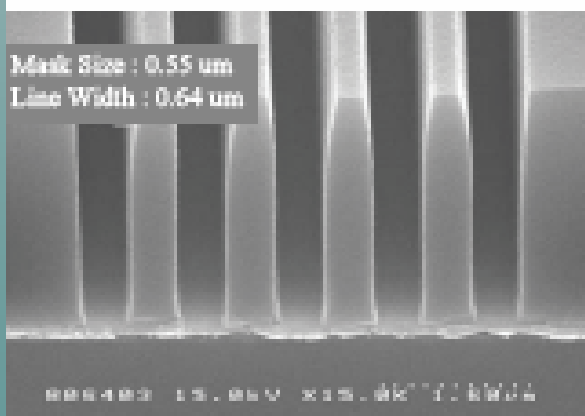
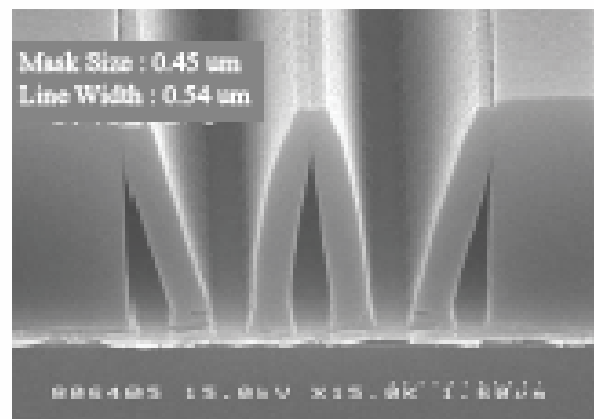
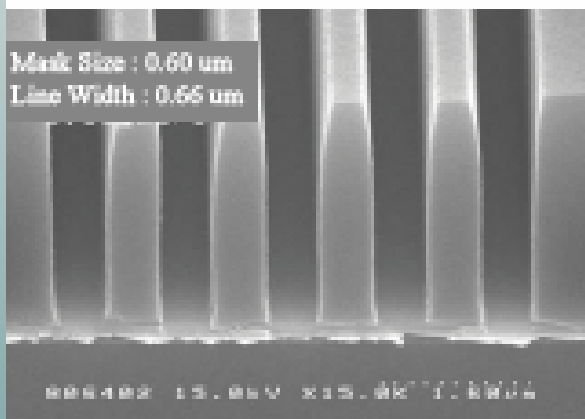
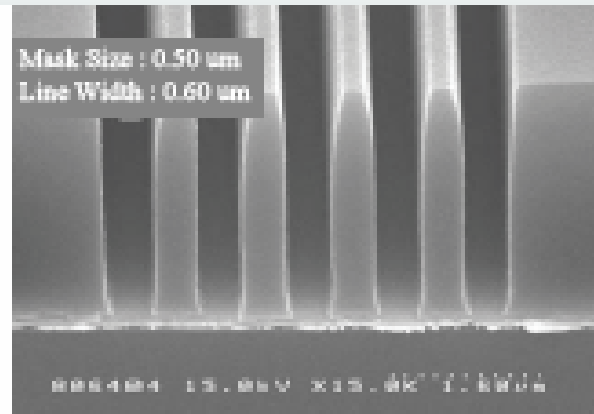
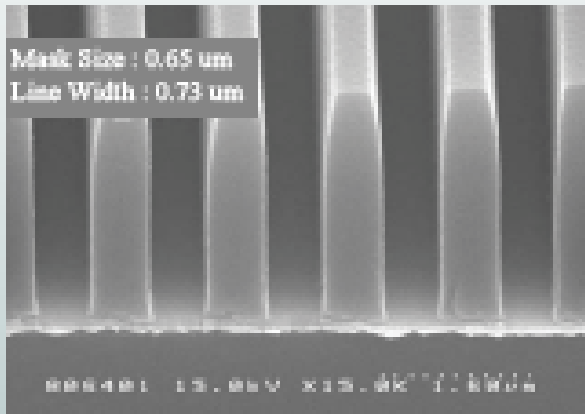
(FT: 3.5 μm , Exp.:65mJ/cm²,
Focus: $\pm 0.0 \mu\text{m}$)

Film Thickness:3.5 μm Prebake: 120°Cx240 sec

Exp.: 65mJ/cm² (NSR-2005Ex8A , NA = 0.50, $\sigma = 0.70$)

Mask: 0.65 . 0.60. 0.55. 0.50 . 0.45 . 0.40 μm (S/L =1/1) Focus: $\pm 0.0 \mu\text{m}$

PED: 30 min., PEB: 100°C x 120 sec Dev.: 50 sec x 3 puddles (SSFD-238N)



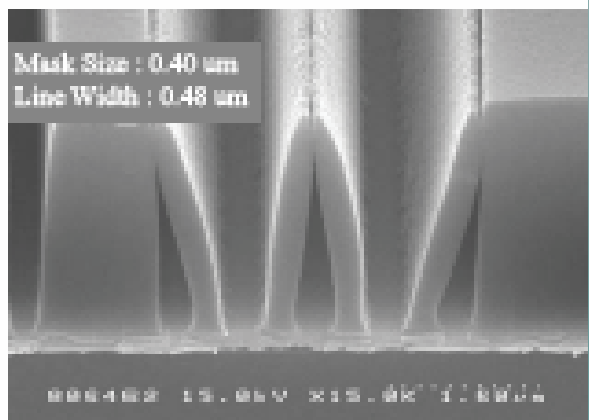
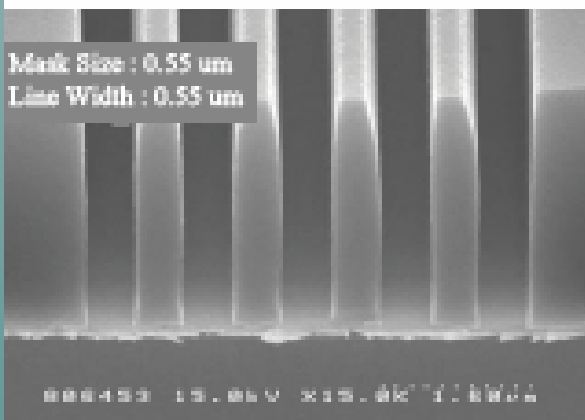
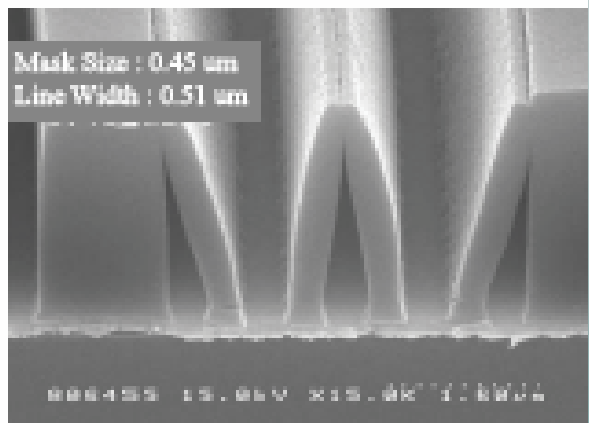
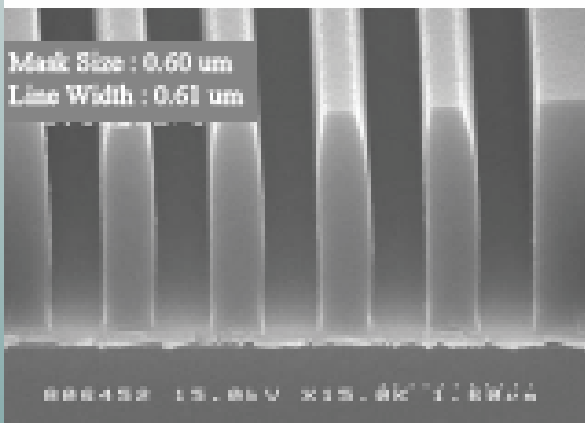
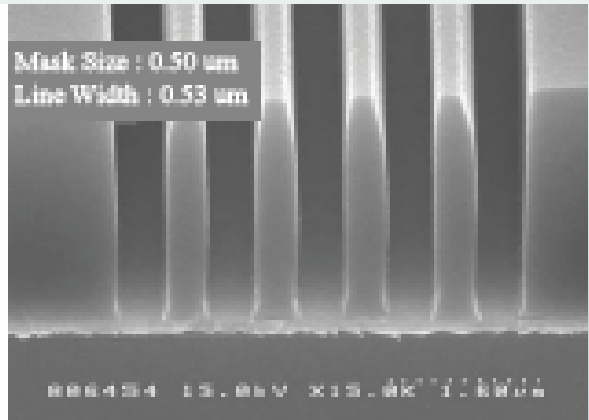
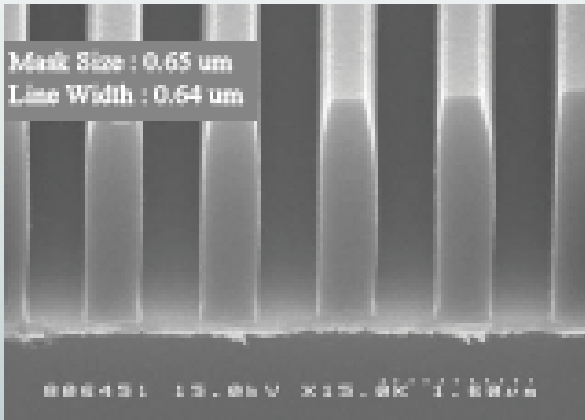
(FT: 3.5 μm , Exp.: 70mJ/cm²,
Focus: $\pm 0.0 \mu\text{m}$)

Film Thickness: 3.5 μm Prebake: 120°C x 240 sec

Exp.: 70mJ/cm² (NSR-2005Ex8A, NA = 0.50, $\sigma = 0.70$)

Mask: 0.65 . 0.60 . 0.55 . 0.50 . 0.45 . 0.40 μm (S/L = 1/1) Focus: $\pm 0.0 \mu\text{m}$

PED: 30 min., PEB: 100°C x 120 sec Dev.: 50 sec x 3 puddles (SSFD-238N)



(FT: 3.5 μm , Exp.:100mJ/cm², Focus: \pm 0.0 μm)

Film Thickness:3.5 μm Prebake: 120°Cx240 sec

Exp.: 100mJ/cm² (NSR-2005Ex8A , NA = 0.50, σ = 0.70)

Mask: 0.65 . 0.60. 0.55. 0.50 . 0.45 . 0.40 μm (S/L =1/1) Focus: \pm 0.0 μm

PED: 30 min., PEB: 100°C x 120 sec

Dev.: 50 sec x 3 puddles (SSFD-238N[TMAH = 2.38%])

